

SENSORDEVICES 2012

Foreword

The Third International Conference on Sensor Device Technologies and Applications [SENSORDEVICES 2012], held between August 19-24, 2012 in Rome, Italy, continued a series of events focusing on sensor devices themselves, the technology-capturing style of sensors, special technologies, signal control and interfaces, and particularly sensors-oriented applications. The evolution of the nano-and microtechnologies, nanomaterials, and the new business services make the sensor device industry and research on sensor-themselves very challenging.

SENSORDEVICES 2012 also featured the following workshop:
- WISH 2012, The Second International Workshop on Intelligent Sensor Hub

We take here the opportunity to warmly thank all the members of the SENSORDEVICES 2012 Technical Program Committee, as well as the numerous reviewers. The creation of such a high quality conference program would not have been possible without their involvement. We also kindly thank all the authors who dedicated much of their time and efforts to contribute to SENSORDEVICES 2012. We truly believe that, thanks to all these efforts, the final conference program consisted of top quality contributions.

Also, this event could not have been a reality without the support of many individuals, organizations, and sponsors. We are grateful to the members of the SENSORDEVICES 2012 organizing committee for their help in handling the logistics and for their work to make this professional meeting a success. We hope that SENSORDEVICES 2012 was a successful international forum for the exchange of ideas and results between academia and industry and for the promotion of progress in the area of sensor device technologies and applications.

We are convinced that the participants found the event useful and communications very open. We also hope the attendees enjoyed the historic charm Rome, Italy.

SENSORDEVICES 2012 Chairs:

Vítor Carvalho, Minho University, Portugal

Irinela Chilibon, National Institute of Research and Development for Optoelectronics - Bucharest, Romania

Petre Dini, Concordia University, Canada / China Space Agency Center, China

Vittorio Ferrari, Università di Brescia, Italy

Elena Gaura, Coventry University, UK

Stephane Gervais-Ducouret, Freescale Semiconductor, Inc., France

Thomas Herzog, Fraunhofer Institute for Non-Destructive Testing IZFP - Dresden, Germany

Henning Heuer, Fraunhofer Institute for Non-Destructive Testing IZFP - Dresden, Germany

Subodh Kumar Singhal, National Physical Laboratory, New Delhi, India

Ksenia V. Sapozhnikova D.I. Mendeleev Institute for Metrology - St. Petersburg, Russia

Raluca - Ioana Stefan-van Staden, National Institute of Research for Electrochemistry and Condensed Matter, Bucharest, Romania

Marco Tartagni, University of Bologna - Cesena, Italy

Dongfang Yang, National Research Council Canada - London, Canada

Alberto Yúfera, Centro Nacional de Microelectronica (CNM-CSIC) - Sevilla, Spain

Sergey Yurish, IFSA - Barcelona, Spain